Application/Control No. Applicant(s)/Patent Under Reexamination 09/852,612 ARATANI ET AL. Notice of References Cited Examiner Art Unit Page 1 of 1 BRIAN P. YENKE 2614 **U.S. PATENT DOCUMENTS Document Number** Date Name Classification Country Code-Number-Kind Code MM-YYYY US-6,373,503 Α 04-2002 Perkes, Ronald M. 715/718 US-6,757,912 В 06-2004 Vaughan et al. 725/139 С US-6,724,351 04-2004 Boger, Robert A. 345/3.2 D US-6,285,406 09-2001 Brusky, Kevin J. 348/552 Ε US-6,200,212 03-2001 Henry et al. 452/194 F US-6,104,390 08-2000 Sturgeon et al. 715/718 US-6,037,994 G 03-2000 Bae, Sang Geun 348/510 US-6,005,550 Н 12-1999 Vaughan et al. 345/157 US-5,926,174 07-1999 Shibamiya et al. 345/213 US-5,819,156 10-1998 J Belmont, Brian V. 725/14 Κ US-6,037,994 03-2000 Bae, Sang Geun 348/510 US-5,819,156 10-1998 L Belmont, Brian V. 725/14 US-5,850,340 М 12-1998 York, Matthew 700/83 **FOREIGN PATENT DOCUMENTS Document Number** Date Country Name Country Code-Number-Kind Code Classification MM-YYYY Ν 0 Р Q R s Т **NON-PATENT DOCUMENTS** Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) U ٧

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